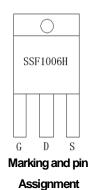
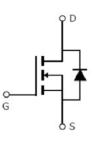


Main Product Characteristics:

V _{DSS}	100V
R _{DS} (on)	5mΩ (typ.)
I _D	200A ①







Schematic diagram

Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

Absolute max Rating:

Symbol	Parameter	Max.	Units	
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	200 ①		
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	130 ①	Α	
I _{DM}	Pulsed Drain Current ②	800		
D @TC 25°C	Power Dissipation ③	500	W	
P _D @TC = 25°C	Linear Derating Factor	3.3	W/°C	
V _{DS}	Drain-Source Voltage	100	V	
V _{GS}	Gate-to-Source Voltage	± 20	V	
E _{AS}	Single Pulse Avalanche Energy @ L=0.3mH	866	mJ	
I _{AS}	Avalanche Current @ L=0.3mH	76	А	
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +175	°C	



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case ③	_	0.3	°C/W
D	Junction-to-ambient (t $\leq 10s)$ \oplus	_	62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	100	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
В	Static Drain-to-Source on-resistance	_	5	6	mΩ	V _{GS} =10V,I _D = 30A
R _{DS(on)}	Static Diam-to-Source on-resistance	_	9.6	_		T _J = 125℃
V	Gate threshold voltage	2	_	4	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
$V_{GS(th)}$	Gate threshold voltage		2.0	-	V	T _J = 125℃
1	Drain to Source leakage gurrent		_	1	^	$V_{DS} = 100V, V_{GS} = 0V$
I _{DSS}	Drain-to-Source leakage current		_	50	μA	T _J = 125°C
Land	Cata to Source forward lookage	1	_	100	nA	V _{GS} =20V
I _{GSS} Gate-to-Source	Gate-to-Source forward leakage	_	_	-100	ΠA	V _{GS} = -20V
Qg	Total gate charge	_	256	_		$I_D = 30A$,
Q_{gs}	Gate-to-Source charge	_	49	_	nC	V _{DS} =30V,
Q_{gd}	Gate-to-Drain("Miller") charge	_	83	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	31	_		V _{GS} =10V, V _{DS} =30V,
t _r	Rise time	_	27	_	nS	
t _{d(off)}	Turn-Off delay time	_	131	_		$R_L=15\Omega, R_{GEN}=2.5\Omega$ $I_D=2A$
tf	Fall time	_	46	_		ID =ZA
C _{iss}	Input capacitance	_	10416	_		V _{GS} = 0V
Coss	Output capacitance	_	690	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	606	_		f =500KHz

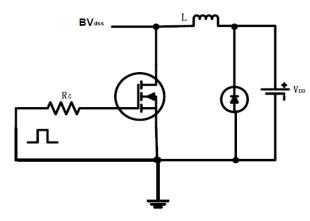
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1	Continuous Source Current			200	۸	MOSFET symbol
I _S	(Body Diode)	_	_	200	A	showing the
	Pulsed Source Current		_	800	А	integral reverse
I _{SM}	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.88	1.3	V	I _S =60A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	46	_	ns	$T_J = 25^{\circ}\text{C}, I_F = 75\text{A},$
Q _{rr}	Reverse Recovery Charge	_	88	_	nC	di/dt = 100A/µs

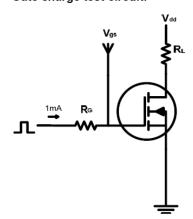


Test circuits and Waveforms

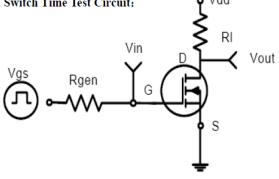
EAS test circuits:



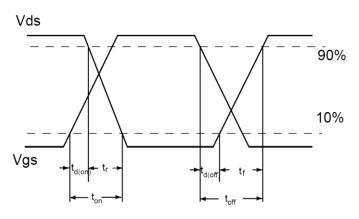
Gate charge test circuit:



Switch Time Test Circuit:



Switch Waveforms:

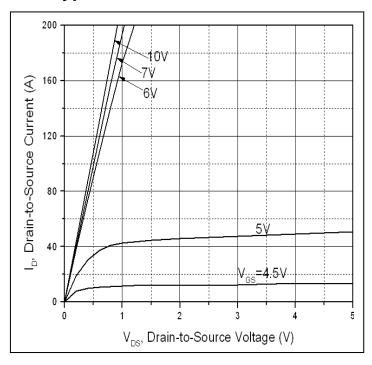


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 156A.
- ②Repetitive rating; pulse width limited by max junction temperature.
- ③The power dissipation PD is based on max junction temperature, using junction-to-case thermal resistance.
- ⓐThe value of R_{θJA} is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics



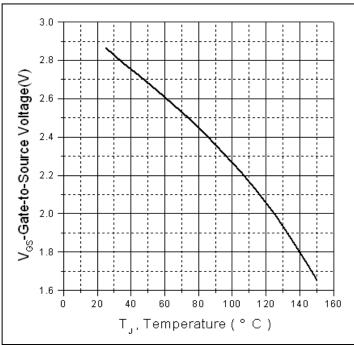


Figure 1: Typical Output Characteristics

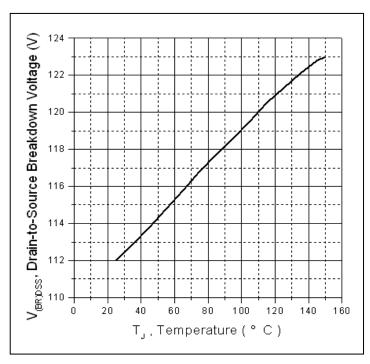


Figure 3. Drain-to-Source Breakdown Voltage Vs.

Case Temperature

Figure 2. Gate to source cut-off voltage

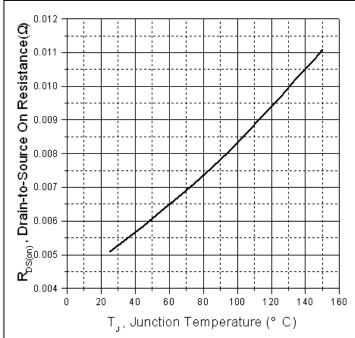
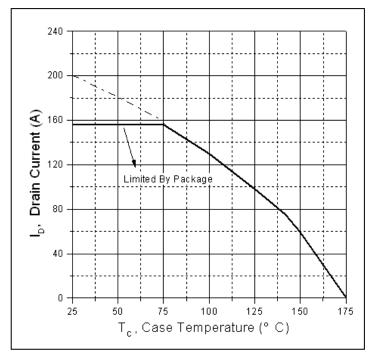


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



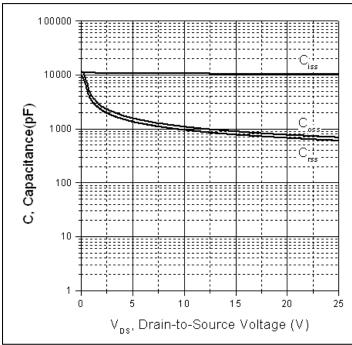
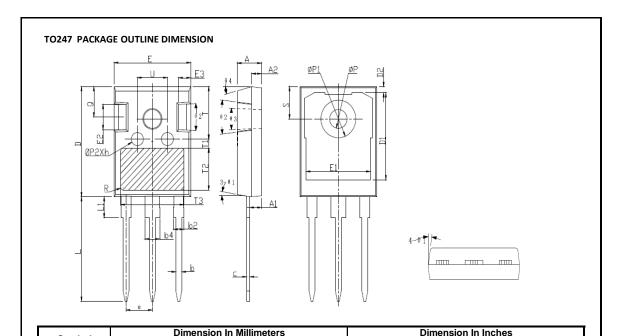


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage



Mechanical Data:



Symbol	Dir	nension In Millime	ters	Dimension In Inches			
Syllibol	Min	Nom	Max	Min	Nom	Max	
Α	4.900	5.000	5.100	0.193	0.197	0.201	
A1	2.310	2.410	2.510	0.091	0.095	0.099	
A2	1.900	2.000	2.100	0.075	0.079	0.083	
b	1.160	1.210	1.260	0.046	0.048	0.050	
b2	1.960	2.010	2.060	0.077	0.079	0.081	
b4	2.960	3.010	3.060	0.117	0.119	0.120	
С	0.590	0.610	0.660	0.023	0.024	0.026	
D	20.900	21.000	21.100	0.823	0.827	0.831	
D1	16.250	16.550	16.850	0.640	0.652	0.663	
D2	1.050	1.200	1.350	0.041	0.047	0.053	
E	15.700	15.800	15.900	0.618	0.622	0.626	
E1	13.100	13.300	13.500	0.516	0.524	0.531	
E2	4.900	5.000	5.100	0.193	0.197	0.201	
E3	2.400	2.500	2.600	0.094	0.098	0.102	
e		5.44BSC			0.214BSC		
h	0.050	0.100	0.150	0.002	0.004	0.006	
L	19.800	19.920	20.100	0.780	0.784	0.791	
L1	-	-	4.300	-	-	0.169	
ΦР	3.500	3.600	3.700	0.138	0.142	0.146	
ФР1	-	-	7.300	-	-	0.287	
ФР2	2.400	2.500	2.600	0.094	0.098	0.102	
Q	5.600	5.800	6.000	0.220	0.228	0.236	
S		6.15BSC	•	0.242BSC			
R		0.50BSC			0.020BSC		
T	9.800	-	10.200	0.386	-	0.402	
T1		1.65REF			0.065REF		
T2	8.00REF		0.315REF				
T3		12.80REF		0.504REF			
U	6.000	-	6.400	0.236	-	0.252	
θ1	6°	7°	8°	6°	7°	8°	
θ2	4°	5°	6°	4°	5°	6°	
θ3	1°	-	1.5°	1°	-	1.5°	
θ4	14°	15°	16°	14°	15°	16°	



Ordering and Marking Information

Device Marking: SSF1006H

Package (Available)
TO-247
Operating Temperature Range
C: -55 to 175 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Туре	Tube	Box	Box	Boxes/Carton	Box
1				_	
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 175℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ or 175℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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